NAME

CUTEST_cifn_threaded - CUTEst tool to evaluate a problem function value.

SYNOPSIS

CALL CUTEST_cifn_threaded(status, n, iprob, X, fn, thread)

For real rather than double precision arguments, instead

CALL CUTEST_cifn_threaded_s(...)

DESCRIPTION

The CUTEST_cifn_threaded subroutine evaluates the value of either the objective function or a constraint function of the problem decoded from a SIF file by the script *sifdecoder* at the point X, in the constrained minimization case. The problem under consideration is to minimize or maximize an objective function f(x) over all $x \in R^n$ subject to general equations $c_i(x) = 0$, $(i \in 1, ..., m_E)$, general inequalities $c_i^l \le c_i(x) \le c_i^u$, $(i \in m_E + 1, ..., m)$, and simple bounds $x^l \le x \le x^u$. The objective function is group-partially separable and all constraint functions are partially separable.

ARGUMENTS

The arguments of CUTEST_cifn_threaded are as follows

status [out] - integer

the outputr status: 0 for a successful call, 1 for an array allocation/deallocation error, 2 for an array bound error, 3 for an evaluation error, 4 for an out-of-range thread,

n [in] - integer

the number of variables for the problem,

iprob [in] - integer

the number of the problem function to be considered. If iprob = 0, the value of the objective function will be evaluated, while if iprob = i > 0, that of the i-th constraint will be evaluated,

X [in] - real/double precision

an array which gives the current estimate of the solution of the problem,

fn [out] - real/double precision

the value of problem function iprob at X,

thread [in] - integer

thread chosen for the evaluation; threads are numbered from 1 to the value threads set when calling CUTEST_csetup_threaded.

AUTHORS

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SEE ALSO

CUTEst: a Constrained and Unconstrained Testing Environment with safe threads,

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CUTEr (and SifDec): A Constrained and Unconstrained Testing Environment, revisited,

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ACM TOMS, 29:4, pp.373-394, 2003.

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sifdecoder(1), cutest_setup_threaded(3M).